Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/777,026	KAWAGUCHI ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED				
Class	Subclass	Date	Examiner	
216	68	7/23/2007	BT	
216	69	7/23/2007	ВТ	
216	73	7/23/2007	ВТ	
438	715	7/23/2007	ВТ	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Updated search using databases in EAST	7/23/2007	вт
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